# **Test Data Referencing**

Justification of Test Data Referencing, for EMC/RF and SAR

Parent model: FCC ID: 2AH25F962A

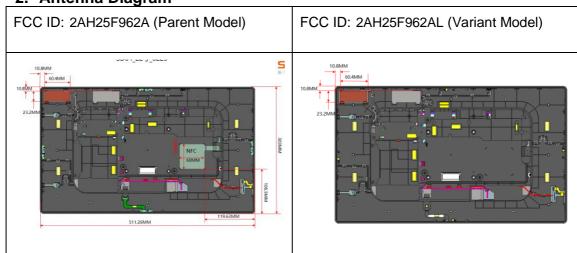
• Variant model: FCC ID: 2AH25F962AL

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## 1. Product Overview

Radio	FCC Rule Part	FCC ID: 2AH25F962A	FCC ID: 2AH25F962AL
Wi-Fi, 2.4, 5 GHz	Part 15	Supported	Supported
ВТ	Part 15	Supported	Supported
NFC	Part 15	Supported	Not Support

2. Antenna Diagram



FC ID 2AH25F962A: Antenna		FC ID 2AH25F962AL: Antenna		
Antenna No. Band support		Band support		
Antenna 1	WiFi 2.4G; WiFi 5G; BT	WiFi 2.4G; WiFi 5G; BT		
NFC ANT:	NFC_13.56 MHz	NA		

## 3. Comparison - Summary

### 3.1 Identical

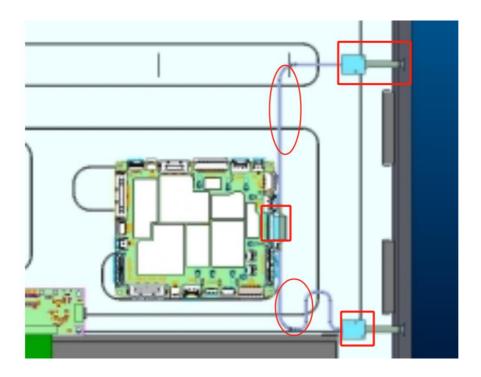
FCC ID: 2AH25F962A, FCC ID: 2AH25F962AL are identical in the followings:

- The device form factor, the size of display area and the housing material is identical
- Enclosure and material
- PCB Layout

#### 3.2 Difference:

FCC ID 2AH25F962AL (Variant model) is different from FCC ID 2AH25F962A (Parent model), in the followings:

- Delete 4pcs USB sub-board and the 4pcs cables between main board and the USB sub-board.
- Delete NFC Antenna FPC
- Delete 2pcs MIC FPC and 2 cables+1pcs Switching FPC from MB(FPC is shown at the red box in the figure below, and cable is shown at the red circle in the figure below)



### 4. Test Strategy

- FCC ID 2AH25F962A: parent model, full test for EMC/RF/Exposure.
- FCC ID 2AH25F962AL: variant model, data referencing from the reference model for EMC/RF and Exposure.
  - EMC/RF/ Exposure spot check justification: Reference KDB484596 D01 Referencing Test Data v03
    - a) EMC Test Data Spot-Checks

These exhibits for the variant certification shall meet the following criteria:

- Spot-check measurements must correspond to the worst-case scenario reported in the parent device filing, i.e., for conditions closest to noncompliance.
- Spot-check measurements must always show compliance with the rule part(s) applicable to the test under consideration.
- Spot-check measurements may show deviations from the reference data, as specified in sub-sections 3.2.1 and 3.2.2. These specifications differ between EMC data and RF exposure test data.

For EMC compliance test data (e.g., spurious emissions limits), the deviation between the variant and the parent model, for both field and power quantities, is expressed as:

$$d_{dB} = |V_{dB} - R_{dB}| (1)$$
,

where *VdB* is the variant spot-check level in dB, and *RdB* is the corresponding reference measurement level in dB for the parent model.

The spot-check will be deemed acceptable when:

$$d_{dB} \leq d_{dBmax}(2)$$
,

where  $d_{dBmax}$  is the maximum deviation  $d_{dB}$  allowed for the EMC data for the spot-check to be considered acceptable. The definition of  $d_{dBmax}$  is based on "how far" the reference data  $R_{dB}$  is from the compliance threshold  $C_{dB}$  (also expressed in dB), for the test under consideration. More specifically, if  $M_{dB}$  is the margin in dB from the compliance limit, expressed as

$$M_{dB} = |C_{dB} - R_{dB}| (3) ,$$

then  $d_{dBmax}$  is defined as a function of  $M_{dB}$ , which increases linearly from 3 dB to 6 dB (Fig. 2), according to:

$$d_{dBmax}(M_{dB}) = (3 + M_{dB}/20) dB , \text{ for } 0 \le M_{dB} \le 60 dB$$
 
$$d_{dBmax}(M_{dB}) = (4) .$$
 
$$6 dB , \text{ for } M_{dB} > 60 dB$$

b) The Spot-Check Plan for RF Exposure Test Data

By expressing all the quantities in linear units, an RF exposure spot-check must be accepted based on the maximum relative difference between the variant and the parent model test results.

The spot-check acceptance criterion is formulated in terms of the total exposure ratio (TER) to easily include RF exposure evaluations based on MPE and evaluations for simultaneous transmissions, (that may include a mix of MPE and SAR evaluations but not for incident power density related to frequencies above 6 GHz).

Accordingly, proceeding in a similar way to the previous section but operating in linear units, the relative difference (expressed as a percentage) between the TER of the variant (*TERV*) and that of the parent model used as a reference (*TERR*) is defined as

$$d_{TER} = |TER_V - TER_R| / TER_R$$
 (5),

and the acceptance criterion for the spot-check on the variant will be:

$$d_{TER} \leq d_{TERmax}$$
 (6),

where  $d_{TERmax}$ , to be defined further below, is the maximum acceptable  $d_{TER}$ , and all the quantities are expressed in linear units.

It is also important to note that if the MPE is considered to refer to a field quantity and not power, the corresponding TER is to be computed as the square of the field ratio, consistent with the other terms that refer to power levels.

The value of  $d_{TERmax}$ , the maximum  $d_{TER}$  allowed for the spot-check to be deemed acceptable, is established based on the compliance margin M corresponding to the worst-case test scenario (i.e., the most challenging from the compliance perspective) for the parent model.

The margin M is defined as

$$M = TER_T - TER_R = 1 - TER_R (7)$$
,

where  $TER_T$  is the TER corresponding to the compliance threshold, which is always  $TER_T = 1$ .

For instance, for a general population evaluation, SAR  $\leq$  1.6 W/kg, as required for any compliant measurement. Thus, since TER = SAR/1.6, and  $0 \leq$  TER  $\leq$  1, then M in eq. (7) will always be a positive number because  $TER_R$  cannot be larger than 1 for the parent model to be complaint.

The threshold  $d_{TERmax}$  is defined as function of the margin M to provide values between 25% and 50%, linearly increasing between M = 0.5 (50% of the compliance limit) and M = 0.75 (75% of the compliance limit), in accordance with the following expression:

$$0.25$$
 , for  $0 \le M < 0.5$   
 $dTERmax(M) = M - 0.25$  , for  $0.5 \le M < 0.75$  (8) .  
 $0.5$  , for  $0.5 \le M$ 

- Compliance is determined by both the spot check data and the referenced test data.
- > Test strategy is tabulated in next page

Band	Rule Part		Parent model FCC ID 2AH25F962A	Variant model FCC ID 2AH25F962AL	
		Test item		Data Referencing	Remark
вт	15.207	AC Power Line Conducted Emission	Full Test	Υ	reuse Parent data
	15.207	Conducted Peak Output Power	Full Test	Υ	Check Worse
	15.247 (b)(1)	20dB Emission Bandwidth & 99% Occupied Bandwidth	Full Test	Υ	reuse Parent data
	15.247 (a)(1)	Carrier Frequencies Separation	Full Test	Υ	reuse Parent data
	15.247 (a)(1)	Hopping Channel Number	Full Test	Υ	reuse Parent data
	15.247 (a)(1)	Dwell Time	Full Test	Υ	reuse Parent data
	15.247 (a)(1)	Band-edge for RF Conducted Emissions	Full Test	Υ	reuse Parent data
	15.247(d)	RF Conducted Spurious Emissions	Full Test	Υ	reuse Parent data
	15.247(d); 15.205/15.209	Radiated Spurious emissions	Full Test	Υ	Check Worse
	15.247(d); 15.205/15.209	Restricted bands around fundamental frequency	Full Test	Υ	Check Worse
	15.207	(Radiated Emission)  AC Power Line Conducted Emission	Full Test	Υ	reuse Parent
	15.247 (b)(3)	Conducted Output Power	Full Test	Y	data Check Worse
	15.247 (a)(2)	DTS (6 dB) Bandwidth & 99% Occupied Bandwidth	Full Test	Υ	reuse Parent data
	15.247 (e)	Power Spectral Density	Full Test	Υ	reuse Parent
BLE	15.247(d)	Band-edge for RF Conducted Emissions	Full Test	Υ	data reuse Parent
	15.247(d)	RF Conducted Spurious Emissions	Full Test	Y	data reuse Parent
	15.205/15.209	Radiated Spurious Emissions	Full Test	Y	data Check Worse
	15.205/15.209	Restricted bands around fundamental	Full Test	Y	Check Worse
	15.207	frequency (Radiated Emission)  AC Power Line Conducted Emission	Full Test	Y	reuse Parent
	15.207 15.247 (b)(3)	Conducted Output Power	Full Test	Y	data Check Worse
	15.247 (b)(3)	DTS (6 dB) Bandwidth & 99% Occupied	Full Test	Y	reuse Parent
	15.247 (e)	Bandwidth Power Spectral Density	Full Test	Υ	reuse Parent
2.4G WIFI	15.247(d)	Band-edge for RF Conducted Emissions	Full Test	Y	data reuse Parent
	15.247(d)	RF Conducted Spurious Emissions	Full Test	Υ	data reuse Parent
	15.205/15.209	Radiated Spurious Emissions	Full Test	Y	data Check Worse
	15.205/15.209	Restricted bands around fundamental frequency (Radiated Emission)	Full Test	Y	Check Worse
5G WIFI	Band I: 15.407(a)(1) Band II-A: 15.407(a)(2) Band II-C: 15.407(a)(2) Band III: 15.407(e)	26dB Emission Bandwidth 26dB Emission Bandwidth 26dB Emission Bandwidth 6dB Emission Bandwidth	Full Test	Y	reuse Parent data
	Band I&Band II-A&Band II-C &Band III: KDB 789033 D02§ D	99% Occupied Bandwidth	Full Test	Υ	reuse Parent data
	Band I: 15.407(a)(iv) Band II-A: 15.407(a)(2) Band II-C: 15.407(a)(2) Band III: 15.407(a)(3)	Maximum Conducted Output Power	Full Test	Y	Check Worse
	Band I: 15.407(a)(iv) Band II-A: 15.407(a)(2) Band II-C: 15.407(a)(2) Band III: 15.407(a)(3)	Maximum Power Spectral Density	Full Test	Y	reuse Parent data
	Band I&Band II-A&Band II-C &Band III: 15.407(b) 15.205/15.209	Radiated Spurious Emissions	Full Test	Υ	Check Worse
	Band I&Band II-A&Band II-C &Band III: 15.407(b) 15.205/15.209	Restricted bands around fundamental frequency	Full Test	Υ	Check Worse
	Band I&Band II-A&Band II-C &Band III: 15.207	AC Power Line Conducted Emissions	Full Test	Υ	reuse Parent data
	Band II-A &Band II-C: 15.407	Dynamic Frequency Selection	Full Test	Υ	reuse Parent data
	Band I&Band II-A&Band II-C &Band III: 15.407(g)	Frequency Stability	Full Test	Y	reuse Parent data
EMI	Part 15B	AC Conducted Emission	Full Test	Υ	Check Worse
		Radiated Emission	Full Test	Υ	Check Worse
MPE	2.1091	RF Exposure Evaluation	Full Test	N	Full